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## Contents

<b>Section 1: Test and Defect Tolerance for Crossbar-Based Architectures</b>	
<i>M. Tehranipoor</i> .....	1
<b>Chapter 1: Defect-Tolerant Logic with Nanoscale Crossbar Circuits</b>	
<i>T. Hogg and G. Snider</i> .....	5
<b>Chapter 2: Built-in Self-Test and Defect Tolerance in Molecular Electronics-Based Nanofabrics</b>	
<i>Z. Wang and K. Chakrabarty</i> .....	33
<b>Chapter 3: Test and Defect Tolerance for Reconfigurable Nanoscale Devices</b>	
<i>M. Tehranipoor and R. Rad</i> .....	63
<b>Chapter 4: A Built-In Self-Test and Diagnosis Strategy for Chemically-Assembled Electronic Nanotechnology</b>	
<i>J.G. Brown and R.D. (Shawn) Blanton</i> .....	95
<b>Chapter 5: Defect Tolerance in Crossbar Array Nano-Architectures</b>	
<i>M.B. Tahoori</i> .....	121
<b>Section 2: Test and Defect Tolerance for QCA Circuits</b>	
<i>M. Tehranipoor</i> .....	153
<b>Chapter 6: Reversible and Testable Circuits for Molecular QCA Design</b>	
<i>X. Ma, J. Huang, C. Metra, and F. Lombardi</i> .....	157

<b>Chapter 7: Cellular Array-Based Delay-Insensitive Asynchronous Circuits Design and Test for Nanocomputing Systems</b>	
<i>J. Di and P.K. Lala</i> . . . . .	203
<b>Chapter 8: QCA Circuits for Robust Coplanar Crossing</b>	
<i>S. Bhanja, M. Ottavi, S. Pontarelli, and F. Lombardi</i> . . . . .	227
<b>Chapter 9: Reliability and Defect Tolerance in Metallic Quantum-Dot Cellular Automata</b>	
<i>M. Liu and C.S. Lent</i> . . . . .	251
<b>Section 3: Testing Microfluidic Biochips</b>	
<i>M. Tehranipoor</i> . . . . .	265
<b>Chapter 10: Test Planning and Test Resource Optimization for Droplet-Based Microfluidic Systems</b>	
<i>F. Su, S. Ozev, and K. Chakrabarty</i> . . . . .	267
<b>Chapter 11: Testing and Diagnosis of Realistic Defects in Digital Microfluidic Biochips</b>	
<i>F. Su, W. Hwang, A. Mukherjee, and K. Chakrabarty</i> . . . . .	287
<b>Section 4: Reliability for Nanotechnology Devices</b>	
<i>M. Tehranipoor</i> . . . . .	313
<b>Chapter 12: Designing Nanoscale Logic Circuits Based on Principles of Markov Random Fields</b>	
<i>K. Nepal, R.I. Bahar, J. Mundy, W.R. Patterson, and A. Zaslavsky</i> . . . .	315
<b>Chapter 13: Towards Nanoelectronics Processor Architectures</b>	
<i>W. Rao, A. Orailoglu, and R. Karri</i> . . . . .	339
<b>Chapter 14: Design and Analysis of Fault-Tolerant Molecular Computing Systems</b>	
<i>D. Bhaduri, S.K. Shukla, H. Quinn, P. Graham, and M. Gokhale</i> . . . . .	373
<b>Index</b> . . . . .	399

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